# Fabrication and Testing of Micro-Cylindrical Ion Trap Arrays for Miniaturized Mass Spectrometer Development

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## Miniaturization and Microfabrication of Cylindrical Ion Trap (CIT) Mass Spectrometers

- Miniaturize ion trap mass spectrometers
  - Low power and portable
- Array approach
  - High sensitivity and parallel analysis
- Microfabrication
  - High precision and batch fabrication





## **Cylindrical Ion Trap Easier to Miniaturize**



Axial modulation often used to improve resolution



# Computer Simulations to Optimize $\mu$ -CIT Geometry ( $z_o/r_o$ )



### Buffer Gas Simulations Indicate µ-CITs can Operate in Low Vacuum

- Simulated spectra obtained from SIMION for a range of pressures inside the CIT with  $z_0/r_0 = 0.97$
- ~360 μm radii μ-CITs,
  m/z = 40 & 50 (200 ions/ea)
- Simulations indicate good performance of micro traps at relatively higher pressures
- No high-vacuum pump?



### **Microfabrication Provides Uniform 3-D Structures**

- Create high-aspect-ratio structures in silicon with high precision
- Arrays of half-CITs bonded backto-back
- Capacitance reduced by etching excess silicon
- Simulations indicate axial modulation required
  - Strong influence of higherorder multipoles







# Microfabrication Approach for CIT Array in Silicon

- Wafer-level batch fabrication approach
- CIT structural layer
  - Ring electrode: Au-coated Si (350 µm)
  - Endplate electrode: Au-coated  $Si_3N_4$  (3  $\mu m$  )
  - Dielectric gap: 5  $\mu$ m thermally grown SiO<sub>2</sub>
  - Cr/Au layer: 150/2500 Å
  - A range of radii (325–375 µm) was incorporated in the optical mask to account for variation in wafer thickness
- Processes used
  - i-line lithography, RIE, DRIE, metal sputtering, dicing, flip chip bonding, Au wire bonding, SEM analysis, Wyko surface analysis



Two arrays of half µ-CITs bonded back-to-back using Au-Au thermocompression bonding

## **KOH Etch after DRIE to Smooth Electrodes**



Wall roughness after deep Si etch step in DRIE



Wall roughness after 1.5 min of KOH etching



SEM of  $\mu$ -CIT with aperture diameter 30% of ring electrode diameter (~360  $\mu$ m)



## **Experimental Characterization of** µ-CIT MS Arrays



## **µ-CIT Array Fabrication Iterations**







Generation I

- Developed a process to fabricate
  CITs in Si
- Thermal compression bonding method established
- Feasible SiO<sub>2</sub> & Si<sub>3</sub>N<sub>4</sub> layer thicknesses ascertained
- High capacitance 640 pF

#### Generation II

- Au layer patterned
- Low capacitance 90 pF
- RF testing indicated arcing/plasma generation
- Need for integration with matched ionization source

#### Generation III

- Si etched between µ-CITs
- Device capacitance 265 pF
- Cylinder wall verticality ~ 89°
- Working prototype (low resolution)
- Summation of spectra









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## New Generation µ-CIT Array Fabrication



#### **Generation IV**

- Fabricated in SOI (Silicon-On-Insulator) wafers
- SOI (40 μm device, 5 μm BOX, 350 μm handle)
- Gas channels for direct gas introduction
- Gradient of z<sub>0</sub>/r<sub>0</sub> ratio for fast determination of optimum geometry













# Arrays of $\mu$ -CITs with Gradient of $z_o/r_o$ to Determine Optimum Geometry



	2
SRI_Int_5.0kV 8.0mm x30 SE(M)	1.1.1.1.1.1.1.1.1.1.1.1.1.1.1.1.1.1.1.

z<sub>o</sub> ≈ 360 μm

Ar pressure	RF voltage frequency	Axial modulation frequency	Axial modulation amplitude
6.7 10 <sup>-6</sup> Torr	7.650 MHz	5.675 MHz	<b>77 mV</b> 0-p



## **Unit Mass Resolution**



# **Organic Vapors Analyzed**



## **Isotopes of Chlorine Resolved**





## **Microfabricated Differential Vacuum Chamber**

- Differential chamber (DC) allows more efficient sample introduction
- Increased sensitivity (3x) with apertures 1.2x diameter of CIT apertures
- Pressure gradient allows for testing higher pressures in trap without damaging ion detector
- Investigation into combined inlet system and ionization source



Si wafers with multiple DC chips with different aperture sizes, after etching the  $Si_3N_4$ 





SEM image of a DC chip showing capillary insert and the apertures for electron beam







Schematic of DC

## **Realization of Low-Cost Micro-Mass Spectrometers**

- Requires microfabrication and integration of all Gas Inlets components
- High-density CIT arrays for increased sensitivity
- Matched ionization sources
- Fast high-gain detector for poor vacuum
- Micro vacuum pumps
- Integration into small package





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